

<b>Notice of References Cited</b>	Application/Control No. 10/734,286	Applicant(s)/Patent Under Reexamination SHEN ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,653,052	03-1987	Doi et al.	714/755
*	B	US-4,719,628	01-1988	Ozaki et al.	714/755
*	C	US-5,278,846	01-1994	Okayama et al.	714/755
*	D	US-5,371,751	12-1994	Moriyama, Yoshiaki	714/762
*	E	US-5,392,299	02-1995	Rhines et al.	714/756
*	F	US-5,696,774	12-1997	Inoue et al.	714/755
*	G	US-5,712,861	01-1998	Inoue et al.	714/752
*	H	US-5,920,578	07-1999	Zook, Christopher P.	714/755
*	I	US-6,122,763	09-2000	Pyndiah et al.	714/755
*	J	US-6,292,921 B1	09-2001	Daoudi et al.	714/784
*	K	US-6,389,573 B1	05-2002	Weng, Lih-Jyh	714/784
*	L	US-2004/0088635 A1	05-2004	Kravtchenko, Alexander	714/758
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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